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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

E·XFI

Product Status	Active
Number of LABs/CLBs	6036
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	203
Number of Gates	108000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	256-BGA
Supplier Device Package	256-FPBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx72a-2fg256

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Logic Module Design

The SX-A family architecture is described as a "sea-ofmodules" architecture because the entire floor of the device is covered with a grid of logic modules with virtually no chip area lost to interconnect elements or routing. The Actel SX-A family provides two types of logic modules: the register cell (R-cell) and the combinatorial cell (C-cell).

The R-cell contains a flip-flop featuring asynchronous clear, asynchronous preset, and clock enable, using the S0 and S1 lines control signals (Figure 1-2). The R-cell registers feature programmable clock polarity selectable on a register-by-register basis. This provides additional flexibility while allowing mapping of synthesized functions into the SX-A FPGA. The clock source for the R-cell can be chosen from either the hardwired clock, the routed clocks, or internal logic.

The C-cell implements a range of combinatorial functions of up to five inputs (Figure 1-3). Inclusion of the DB input and its associated inverter function allows up to 4,000 different combinatorial functions to be implemented in a single module. An example of the flexibility enabled by the inversion capability is the ability to integrate a 3-input exclusive-OR function into a single C-cell. This facilitates construction of 9-bit parity-tree functions with 1.9 ns propagation delays.

Module Organization

All C-cell and R-cell logic modules are arranged into horizontal banks called Clusters. There are two types of Clusters: Type 1 contains two C-cells and one R-cell, while Type 2 contains one C-cell and two R-cells.

Clusters are grouped together into SuperClusters (Figure 1-4 on page 1-3). SuperCluster 1 is a two-wide grouping of Type 1 Clusters. SuperCluster 2 is a two-wide group containing one Type 1 Cluster and one Type 2 Cluster. SX-A devices feature more SuperCluster 1 modules than SuperCluster 2 modules because designers typically require significantly more combinatorial logic than flip-flops.



Figure 1-2 • R-Cell



Figure 1-3 • C-Cell



Clock Resources

Actel's high-drive routing structure provides three clock networks (Table 1-1). The first clock, called HCLK, is hardwired from the HCLK buffer to the clock select multiplexor (MUX) in each R-cell. HCLK cannot be connected to combinatorial logic. This provides a fast propagation path for the clock signal. If not used, this pin must be set as Low or High on the board. It must not be left floating. Figure 1-7 describes the clock circuit used for the constant load HCLK and the macros supported.

HCLK does not function until the fourth clock cycle each time the device is powered up to prevent false output levels due to any possible slow power-on-reset signal and fast start-up clock circuit. To activate HCLK from the first cycle, the TRST pin must be reserved in the Design software and the pin must be tied to GND on the board.

Two additional clocks (CLKA, CLKB) are global clocks that can be sourced from external pins or from internal logic signals within the SX-A device. CLKA and CLKB may be connected to sequential cells or to combinational logic. If CLKA or CLKB pins are not used or sourced from signals, these pins must be set as Low or High on the board. They must not be left floating. Figure 1-8 describes the CLKA and CLKB circuit used and the macros supported in SX-A devices with the exception of A54SX72A.

In addition, the A54SX72A device provides four quadrant clocks (QCLKA, QCLKB, QCLKC, and QCLKD corresponding to bottom-left, bottom-right, top-left, and top-right locations on the die, respectively), which can be sourced from external pins or from internal logic signals within the device. Each of these clocks can individually drive up to an entire quadrant of the chip, or they can be grouped together to drive multiple quadrants (Figure 1-9 on page 1-6). QCLK pins can function as user I/O pins. If not used, the QCLK pins must be tied Low or High on the board and must not be left floating.

For more information on how to use quadrant clocks in the A54SX72A device, refer to the *Global Clock Networks in Actel's Antifuse Devices* and *Using A54SX72A and RT54SX72S Quadrant Clocks* application notes.

The CLKA, CLKB, and QCLK circuits for A54SX72A as well as the macros supported are shown in Figure 1-10 on page 1-6. Note that bidirectional clock buffers are only available in A54SX72A. For more information, refer to the "Pin Description" section on page 1-15.

Table 1-1 • SX-A Clock Resources

	A54SX08A	A54SX16A	A54SX32A	A54SX72A
Routed Clocks (CLKA, CLKB)	2	2	2	2
Hardwired Clocks (HCLK)	1	1	1	1
Quadrant Clocks (QCLKA, QCLKB, QCLKC, QCLKD)	0	0	0	4



Figure 1-7 • SX-A HCLK Clock Buffer



Figure 1-8 • SX-A Routed Clock Buffer

JTAG Instructions

Table 1-7 lists the supported instructions with the corresponding IR codes for SX-A devices.

Table 1-8 lists the codes returned after executing the IDCODE instruction for SX-A devices. Note that bit 0 is always '1'. Bits 11-1 are always '02F', which is the Actel manufacturer code.

Table 1-7 •	JTAG	Instruction	Code
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Instructions (IR4:IR0)	Binary Code
EXTEST	00000
SAMPLE/PRELOAD	00001
INTEST	00010
USERCODE	00011
IDCODE	00100
HighZ	01110
CLAMP	01111
Diagnostic	10000
BYPASS	11111
Reserved	All others

Table 1-8 JTAG Instruction Code

Device	Process	Revision	Bits 31-28	Bits 27-12
A54SX08A	0.22 µ	0	8, 9	40B4, 42B4
		1	А, В	40B4, 42B4
A54SX16A	0.22 µ	0	9	4088, 4288
		1	В	4088, 4288
	0.25 µ	1	В	22B8
A54SX32A	0.2 2µ	0	9	40BD, 42BD
		1	В	40BD, 42BD
	0.25 µ	1	В	22BD
A54SX72A	0.22 µ	0	9	40B2, 42B2
		1	В	40B2, 42B2
	0.25 µ	1	В	22B2

SX-A Probe Circuit Control Pins

SX-A devices contain internal probing circuitry that provides built-in access to every node in a design, enabling 100% real-time observation and analysis of a device's internal logic nodes without design iteration. The probe circuitry is accessed by Silicon Explorer II, an easy to use, integrated verification and logic analysis tool that can sample data at 100 MHz (asynchronous) or 66 MHz (synchronous). Silicon Explorer II attaches to a PC's standard COM port, turning the PC into a fully functional 18-channel logic analyzer. Silicon Explorer II allows designers to complete the design verification process at their desks and reduces verification time from several hours per cycle to a few seconds.

The Silicon Explorer II tool uses the boundary-scan ports (TDI, TCK, TMS, and TDO) to select the desired nets for verification. The selected internal nets are assigned to the

PRA/PRB pins for observation. Figure 1-13 illustrates the interconnection between Silicon Explorer II and the FPGA to perform in-circuit verification.

Design Considerations

In order to preserve device probing capabilities, users should avoid using the TDI, TCK, TDO, PRA, and PRB pins as input or bidirectional ports. Since these pins are active during probing, critical input signals through these pins are not available. In addition, the security fuse must not be programmed to preserve probing capabilities. Actel recommends that you use a 70 Ω series termination resistor on every probe connector (TDI, TCK, TMS, TDO, PRA, PRB). The 70 Ω series termination is used to prevent data transmission corruption during probing and reading back the checksum.



Figure 1-13 • Probe Setup

Detailed Specifications

Operating Conditions

Table 2-1 • Absolute Maximum Ratings

Symbol	Parameter	Limits	Units
V _{CCI}	DC Supply Voltage for I/Os	-0.3 to +6.0	V
V _{CCA}	DC Supply Voltage for Arrays	-0.3 to +3.0	V
VI	Input Voltage	–0.5 to +5.75	V
V _O	Output Voltage	–0.5 to + V _{CCI} + 0.5	V
T _{STG}	Storage Temperature	–65 to +150	°C

Note: *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the "Recommended Operating Conditions".

Table 2-2 Recommended Operating Conditions

Parameter	Commercial	Industrial	Units
Temperature Range	0 to +70	–40 to +85	°C
2.5 V Power Supply Range (V _{CCA} and V _{CCI})	2.25 to 2.75	2.25 to 2.75	V
3.3 V Power Supply Range (V _{CCI})	3.0 to 3.6	3.0 to 3.6	V
5 V Power Supply Range (V _{CCI})	4.75 to 5.25	4.75 to 5.25	V

Typical SX-A Standby Current

Table 2-3 • Typical Standby Current for SX-A at 25°C with $V_{CCA} = 2.5 V$

Product	V _{CCI} = 2.5 V	V _{CCI} = 3.3 V	V _{CCI} = 5 V
A54SX08A	0.8 mA	1.0 mA	2.9 mA
A54SX16A	0.8 mA	1.0 mA	2.9 mA
A54SX32A	0.9 mA	1.0 mA	3.0 mA
A54SX72A	3.6 mA	3.8 mA	4.5 mA

Table 2-4 • Supply Voltages

V _{CCA}	V _{CCI} *	Maximum Input Tolerance	Maximum Output Drive
2. 5 V	2.5 V	5.75 V	2.7 V
2.5 V	3.3 V	5.75 V	3.6 V
2.5 V	5 V	5.75 V	5.25 V

Note: *3.3 V PCI is not 5 V tolerant due to the clamp diode, but instead is 3.3 V tolerant.



Where:

- C_{EQCM} = Equivalent capacitance of combinatorial modules (C-cells) in pF
- C_{EQSM} = Equivalent capacitance of sequential modules (R-Cells) in pF
- C_{EQI} = Equivalent capacitance of input buffers in pF
- C_{EQO} = Equivalent capacitance of output buffers in pF
- C_{EQCR} = Equivalent capacitance of CLKA/B in pF
- C_{EQHV} = Variable capacitance of HCLK in pF
- C_{EQHF} = Fixed capacitance of HCLK in pF
 - C_{L =} Output lead capacitance in pF
 - f_m = Average logic module switching rate in MHz
 - $f_n =$ Average input buffer switching rate in MHz
 - f_p = Average output buffer switching rate in MHz
 - $f_{a1} =$ Average CLKA rate in MHz
 - $f_{\alpha 2}$ = Average CLKB rate in MHz
 - f_{s1} = Average HCLK rate in MHz
 - m = Number of logic modules switching at fm
 - n = Number of input buffers switching at fn
 - p = Number of output buffers switching at fp
 - q₁ = Number of clock loads on CLKA
 - q₂ = Number of clock loads on CLKB
 - $r_1 =$ Fixed capacitance due to CLKA
 - r₂ = Fixed capacitance due to CLKB
 - s1 = Number of clock loads on HCLK
 - x = Number of I/Os at logic low
 - y = Number of I/Os at logic high

Table 2-11 • CEQ Values for SX-A Devices

	A54SX08A	A54SX16A	A54SX32A	A54SX72A
Combinatorial modules (C _{EQCM})	1.70 pF	2.00 pF	2.00 pF	1.80 pF
Sequential modules (C _{EQCM})	1.50 pF	1.50 pF	1.30 pF	1.50 pF
Input buffers (C _{EQI})	1.30 pF	1.30 pF	1.30 pF	1.30 pF
Output buffers (C _{EQO})	7.40 pF	7.40 pF	7.40 pF	7.40 pF
Routed array clocks (C _{EQCR})	1.05 pF	1.05 pF	1.05 pF	1.05 pF
Dedicated array clocks – variable (C _{EQHV})	0.85 pF	0.85 pF	0.85 pF	0.85 pF
Dedicated array clocks – fixed (C_{EQHF})	30.00 pF	55.00 pF	110.00 pF	240.00 pF
Routed array clock A (r ₁)	35.00 pF	50.00 pF	90.00 pF	310.00 pF



To determine the heat sink's thermal performance, use the following equation:

$$\theta_{JA(TOTAL)} = \theta_{JC} + \theta_{CS} + \theta_{SA}$$

EQ 2-14

where:

 $\theta_{CS} = 0.37^{\circ}C/W$

 thermal resistance of the interface material between the case and the heat sink, usually provided by the thermal interface manufacturer

 θ_{SA} = thermal resistance of the heat sink in °C/W

 $\theta_{SA} = \theta_{JA(TOTAL)} - \theta_{JC} - \theta_{CS}$ EQ 2-15 $\theta_{SA} = 13.33^{\circ}C/W - 3.20^{\circ}C/W - 0.37^{\circ}C/W$

$$\theta_{SA} = 9.76^{\circ}C/W$$

A heat sink with a thermal resistance of 9.76°C/W or better should be used. Thermal resistance of heat sinks is a function of airflow. The heat sink performance can be significantly improved with the presence of airflow.

Carefully estimating thermal resistance is important in the long-term reliability of an Actel FPGA. Design engineers should always correlate the power consumption of the device with the maximum allowable power dissipation of the package selected for that device, using the provided thermal resistance data.

Note: The values may vary depending on the application.

SX-A Timing Model



Note: *Values shown for A54SX72A, –2, worst-case commercial conditions at 5 V PCI with standard place-and-route. Figure 2-3 • SX-A Timing Model

Sample Path Calculations

Hardwired Clock

External Setup	=	(t _{INYH} + t _{RD1} + t _{SUD}) – t _{HCKH}
	=	0.6 + 0.3 + 0.8 - 1.8 = - 0.1 ns
Clock-to-Out (Pad-to-Pad)	=	t _{HCKH} + t _{RCO} + t _{RD1} + t _{DHL}
	=	1.8 + 0.8 + 0.3 + 3.9 = 6.8 ns

Routed Clock

External Setup	$= (t_{INYH} + t_{RD1} + t_{SUD}) - t_{RC}$	СКН
	= 0.6 + 0.3 + 0.8 - 3.0 = -1.	3 ns
Clock-to-Out (Pad-to-Pad	$= t_{RCKH} + t_{RCO} + t_{RD1} + t_{DH}$	L
	= 3.0 + 0.8 + 0.3 + 3.9 = 8.0) ns

Timing Characteristics

Table 2-14 • A54SX08A Timing Characteristics

(Worst-Case Commercial Conditions, V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)

		-2 S	-2 Speed -1 Speed		Std. Speed		-F Speed			
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
C-Cell Propagation Delays ¹										
t _{PD}	Internal Array Module		0.9		1.1		1.2		1.7	ns
Predicted Ro	outing Delays ²			4						
t _{DC}	FO = 1 Routing Delay, Direct Connect		0.1		0.1		0.1		0.1	ns
t _{FC}	FO = 1 Routing Delay, Fast Connect		0.3		0.3		0.4		0.6	ns
t _{RD1}	FO = 1 Routing Delay		0.3		0.4		0.5		0.6	ns
t _{RD2}	FO = 2 Routing Delay		0.5		0.5		0.6		0.8	ns
t _{RD3}	FO = 3 Routing Delay		0.6		0.7		0.8		1.1	ns
t _{RD4}	FO = 4 Routing Delay		0.8		0.9		1		1.4	ns
t _{RD8}	FO = 8 Routing Delay		1.4		1.5		1.8		2.5	ns
t _{RD12}	FO = 12 Routing Delay		2		2.2		2.6		3.6	ns
R-Cell Timing										
t _{RCO}	Sequential Clock-to-Q		0.7		0.8		0.9		1.3	ns
t _{CLR}	Asynchronous Clear-to-Q		0.6		0.6		0.8		1.0	ns
t _{PRESET}	Asynchronous Preset-to-Q		0.7		0.7		0.9		1.2	ns
t _{sud}	Flip-Flop Data Input Set-Up	0.7		0.8		0.9		1.2		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.4		1.5		1.8		2.5		ns
t _{recasyn}	Asynchronous Recovery Time	0.4		0.4		0.5		0.7		ns
t _{HASYN}	Asynchronous Hold Time	0.3		0.3		0.4		0.6		ns
t _{MPW}	Clock Pulse Width	1.6		1.8		2.1		2.9		ns
Input Modu	le Propagation Delays			1						
t _{INYH}	Input Data Pad to Y High 2.5 V LVCMOS		0.8		0.9		1.0		1.4	ns
t _{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS		1.0		1.2		1.4		1.9	ns
t _{INYH}	Input Data Pad to Y High 3.3 V PCI		0.6		0.6		0.7		1.0	ns
t _{INYL}	Input Data Pad to Y Low 3.3 V PCI		0.7		0.8		0.9		1.3	ns
t _{INYH}	Input Data Pad to Y High 3.3 V LVTTL		0.7		0.7		0.9		1.2	ns
t _{INYL}	Input Data Pad to Y Low 3.3 V LVTTL		1.0		1.1		1.3		1.8	ns

Notes:

1. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-16 A54SX08A Timing Characteristics

(Worst-Case Commercial Conditions	V _{CCA} = 2.25 V, V _{CC}	₁ = 3.0 V, T _J = 70°C)
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		-2 Speed -1 Speed		Std.	Speed	–F Speed				
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Dedicated (H	lardwired) Array Clock Networks									
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.3		1.5		1.7		2.6	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.1		1.3		1.5		2.2	ns
t _{HPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{HPVVL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.4		0.5		0.5		0.8	ns
t _{HP}	Minimum Period	3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		313		278		238		172	MHz
Routed Arra	Routed Array Clock Networks									
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		0.8		0.9		1.1		1.5	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.1		1.2		1.4		2	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		0.8		0.9		1.1		1.5	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.1		1.2		1.4		2	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.1		1.2		1.4		1.9	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.2		1.3		1.6		2.2	ns
t _{RPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{RPVVL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		0.7		0.8		0.9		1.3	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.7		0.8		0.9		1.3	ns
t _{RCKSW}	Maximum Skew (100% Load)		0.8		0.9		1.1		1.5	ns

Table 2-19 • A54SX08A Timing Characteristics

(Worst-Case Commercial Conditions V_{CCA} = 2.25 V, V_{CCI} = 3.0 V, T_J = 70°C)

		-2 Speed		-1 S	peed	Std. S	Speed	–F S	peed	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
3.3 V PCI Ou	tput Module Timing ¹									
t _{DLH}	Data-to-Pad Low to High		2.2		2.4		2.9		4.0	ns
t _{DHL}	Data-to-Pad High to Low		2.3		2.6		3.1		4.3	ns
t _{ENZL}	Enable-to-Pad, Z to L		1.7		1.9		2.2		3.1	ns
t _{ENZH}	Enable-to-Pad, Z to H		2.2		2.4		2.9		4.0	ns
t _{ENLZ}	Enable-to-Pad, L to Z		2.8		3.2		3.8		5.3	ns
t _{ENHZ}	Enable-to-Pad, H to Z		2.3		2.6		3.1		4.3	ns
d_{TLH}^2	Delta Low to High		0.03		0.03		0.04		0.045	ns/pF
d_{THL}^2	Delta High to Low		0.015		0.015		0.015		0.025	ns/pF
3.3 V LVTTL O	Dutput Module Timing ³							-		
t _{DLH}	Data-to-Pad Low to High		3.0		3.4		4.0		5.6	ns
t _{DHL}	Data-to-Pad High to Low		3.0		3.3		3.9		5.5	ns
t _{DHLS}	Data-to-Pad High to Low—low slew		10.4		11.8		13.8		19.3	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.6		2.9		3.4		4.8	ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew		18.9		21.3		25.4		34.9	ns
t _{ENZH}	Enable-to-Pad, Z to H		3		3.4		4		5.6	ns
t _{ENLZ}	Enable-to-Pad, L to Z		3.3		3.7		4.4		6.2	ns
t _{ENHZ}	Enable-to-Pad, H to Z		3		3.3		3.9		5.5	ns
d_{TLH}^{2}	Delta Low to High		0.03		0.03		0.04		0.045	ns/pF
d_{THL}^2	Delta High to Low		0.015		0.015		0.015		0.025	ns/pF
d_{THLS}^2	Delta High to Low—low slew		0.053		0.067		0.073		0.107	ns/pF

Notes:

1. Delays based on 10 pF loading and 25 Ω resistance.

2. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation: Slew Rate $[V/ns] = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$ where C_{load} is the load capacitance driven by the I/O in pF

 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

3. Delays based on 35 pF loading.

Table 2-24 A54SX16A Timing Characteristics

(Worst-Case Commercial Condition	s V _{CCA} = 2.25 V, V _{CCI} =4.75 V	', Τ _J = 70°C)
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		-3 Sp	peed*	-2 Speed		-1 S	peed	Std. Speed		-F Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Dedicated (Hardwired) Array Clock Networks										1		
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.2		1.4		1.6		1.8		2.8	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.0		1.1		1.2		1.5		2.2	ns
t _{HPWH}	Minimum Pulse Width High	1.4		1.7		1.9		2.2		3.0		ns
t _{HPVVL}	Minimum Pulse Width Low	1.4		1.7		1.9		2.2		3.0		ns
t _{HCKSW}	Maximum Skew		0.3		0.3		0.4		0.4		0.7	ns
t _{HP}	Minimum Period	2.8		3.4		3.8		4.4		6.0		ns
f _{HMAX}	Maximum Frequency		357		294		263		227		167	MHz
Routed Arr	Routed Array Clock Networks											
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		1.0		1.2		1.3		1.6		2.2	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.1		1.3		1.5		1.7		2.4	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.3		1.5		1.7		2.0		2.8	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.3		1.5		1.7		2.0		2.8	ns
t _{RPWH}	Minimum Pulse Width High	1.4		1.7		1.9		2.2		3.0		ns
t _{RPWL}	Minimum Pulse Width Low	1.4		1.7		1.9		2.2		3.0		ns
t _{RCKSW}	Maximum Skew (Light Load)		0.8		0.9		1.0		1.2		1.7	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.8		0.9		1.0		1.2		1.7	ns
t _{RCKSW}	Maximum Skew (100% Load)		1.0		1.1		1.3		1.5		2.1	ns

Note: **All* –3 speed grades have been discontinued.

Table 2-35 A545X72A Timing Characteristics (Continued)

		-3 Speed ¹		-2 Speed		-1 Speed		Std. Speed		-F Speed		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t _{INYH}	Input Data Pad to Y High 5 V PCI		0.5		0.6		0.7		0.8		1.1	ns
t _{INYL}	Input Data Pad to Y Low 5 V PCI		0.8		0.9		1.0		1.2		1.6	ns
t _{INYH}	Input Data Pad to Y High 5 V TTL		0.7		0.8		0.9		1.0		1.4	ns
t _{INYL}	Input Data Pad to Y Low 5 V TTL		0.9		1.1		1.2		1.4		1.9	ns
Input Modu	le Predicted Routing Delays ³											
t _{IRD1}	FO = 1 Routing Delay		0.3		0.3		0.4		0.5		0.7	ns
t _{IRD2}	FO = 2 Routing Delay		0.4		0.5		0.6		0.7		1	ns
t _{IRD3}	FO = 3 Routing Delay		0.5		0.7		0.8		0.9		1.3	ns
t _{IRD4}	FO = 4 Routing Delay		0.7		0.9		1		1.1		1.5	ns
t _{IRD8}	FO = 8 Routing Delay		1.2		1.5		1.7		2.1		2.9	ns
t _{IRD12}	FO = 12 Routing Delay		1.7		2.2		2.5		3		4.2	ns

(Worst-Case Commercial Conditions, $V_{CCA} = 2.25 \text{ V}$, $V_{CCI} = 3.0 \text{ V}$, $T_J = 70^{\circ}\text{C}$)

Notes:

1. All –3 speed grades have been discontinued.

2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.

3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.



Package Pin Assignments

208-Pin PQFP



Figure 3-1 • 208-Pin PQFP (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at http://www.actel.com/products/rescenter/package/index.html.

100-TQFP			100-TQFP							
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function			
1	GND	GND	GND	36	GND	GND	GND			
2	TDI, I/O	TDI, I/O	TDI, I/O	37	NC	NC	NC			
3	I/O	I/O	I/O	38	I/O	I/O	I/O			
4	I/O	I/O	I/O	39	HCLK	HCLK	HCLK			
5	I/O	I/O	I/O	40	I/O	I/O	I/O			
6	I/O	I/O	I/O	41	I/O	I/O	I/O			
7	TMS	TMS	TMS	42	I/O	I/O	I/O			
8	V _{CCI}	V _{CCI}	V _{CCI}	43	I/O	I/O	I/O			
9	GND	GND	GND	44	V _{CCI}	V _{CCI}	V _{CCI}			
10	I/O	I/O	I/O	45	I/O	I/O	I/O			
11	I/O	I/O	I/O	46	I/O	I/O	I/O			
12	I/O	I/O	I/O	47	I/O	I/O	I/O			
13	I/O	I/O	I/O	48	I/O	I/O	I/O			
14	I/O	I/O	I/O	49	TDO, I/O	TDO, I/O	TDO, I/O			
15	I/O	I/O	I/O	50	I/O	I/O	I/O			
16	TRST, I/O	TRST, I/O	trst, I/O	51	GND	GND	GND			
17	I/O	I/O	I/O	52	I/O	I/O	I/O			
18	I/O	I/O	I/O	53	I/O	I/O	I/O			
19	I/O	I/O	I/O	54	I/O	I/O	I/O			
20	V _{CCI}	V _{CCI}	V _{CCI}	55	I/O	I/O	I/O			
21	I/O	I/O	I/O	56	I/O	I/O	I/O			
22	I/O	I/O	I/O	57	V _{CCA}	V _{CCA}	V _{CCA}			
23	I/O	I/O	I/O	58	V _{CCI}	V _{CCI}	V _{CCI}			
24	I/O	I/O	I/O	59	I/O	I/O	I/O			
25	I/O	I/O	I/O	60	I/O	I/O	I/O			
26	I/O	I/O	I/O	61	I/O	I/O	I/O			
27	I/O	I/O	I/O	62	I/O	I/O	I/O			
28	I/O	I/O	I/O	63	I/O	I/O	I/O			
29	I/O	I/O	I/O	64	I/O	I/O	I/O			
30	I/O	I/O	I/O	65	I/O	I/O	I/O			
31	I/O	I/O	I/O	66	I/O	I/O	I/O			
32	I/O	I/O	I/O	67	V _{CCA}	V _{CCA}	V _{CCA}			
33	I/O	I/O	I/O	68	GND	GND	GND			
34	PRB, I/O	PRB, I/O	PRB, I/O	69	GND	GND	GND			
35	V _{CCA}	V _{CCA}	V _{CCA}	70	I/O	I/O	I/O			



329-Pin PBGA					
Pin Number	A54SX32A Function				
V22	I/O				
V23	I/O				
W1	I/O				
W2	I/O				
W3	I/O				
W4	I/O				
W20	I/O				
W21	I/O				
W22	I/O				
W23	NC				
Y1	NC				
Y2	I/O				
Y3	I/O				
Y4	GND				
Y5	I/O				
Y6	I/O				
Y7	I/O				
Y8	I/O				
Y9	I/O				
Y10	I/O				
Y11	I/O				
Y12	V _{CCA}				
Y13	NC				
Y14	I/O				
Y15	I/O				
Y16	I/O				
Y17	I/O				
Y18	I/O				
Y19	I/O				
Y20	GND				
Y21	I/O				
Y22	I/O				
Y23	I/O				



256-Pin FBGA



Figure 3-7 • 256-Pin FBGA (Top View)

Note

For Package Manufacturing and Environmental information, visit Resource center at http://www.actel.com/products/rescenter/package/index.html.

	Actel	
SX-A Fa	amily FPGAs	

484-Pin FBGA						
Pin Number	A54SX32A Function	A54SX72A Function				
T3	I/O	I/O				
T4	I/O	I/O				
T5	I/O	I/O				
T10	GND	GND				
T11	GND	GND				
T12	GND	GND				
T13	GND	GND				
T14	GND	GND				
T15	GND	GND				
T16	GND	GND				
T17	GND	GND				
T22	I/O	I/O				
T23	I/O	I/O				
T24	I/O	I/O				
T25	NC*	I/O				
T26	NC*	I/O				
U1	I/O	I/O				
U2	V _{CCI}	V _{CCI}				
U3	I/O	I/O				
U4	I/O	I/O				
U5	I/O	I/O				
U10	GND	GND				
U11	GND	GND				
U12	GND	GND				
U13	GND	GND				
U14	GND	GND				
U15	GND	GND				
U16	GND	GND				
U17	GND	GND				
U22	I/O	I/O				
U23	I/O	I/O				
U24	I/O	I/O				
U25	V _{CCI}	V _{CCI}				
U26	I/O	I/O				
V1	NC*	I/O				

484-Pin FBGA								
Pin Number	A54SX32A Function	A54SX72A Function						
V2	NC*	I/O						
V3	I/O	I/O						
V4	I/O	I/O						
V5	I/O	I/O						
V22	V _{CCA}	V _{CCA}						
V23	I/O	I/O						
V24	I/O	I/O						
V25	NC*	I/O						
V26	NC*	I/O						
W1	I/O	I/O						
W2	I/O	I/O						
W3	I/O	I/O						
W4	I/O	I/O						
W5	I/O	I/O						
W22	I/O	I/O						
W23	V _{CCA}	V _{CCA}						
W24	I/O	I/O						
W25	NC*	I/O						
W26	NC*	I/O						
Y1	NC*	I/O						
Y2	NC*	I/O						
Y3	I/O	I/O						
Y4	I/O	I/O						
Y5	NC*	I/O						
Y22	I/O	I/O						
Y23	I/O	I/O						
Y24	V _{CCI}	V _{CCI}						
Y25	I/O	I/O						
Y26	I/O	I/O						

Note: *These pins must be left floating on the A54SX32A device.